BLOOMY News From Your Automation Partner



July 2017

Quick Links

Automated Test Equipment

Avionics Real-Time Test Battery Test and Simulation

Speak with an Engineer

We're Hiring!

Windsor, CT **HIL Test Engineer** Electro-Mechanical Assembler

Paramus, NJ **BTS Product Engineer** LabVIEW Systems Engineer

Marlborough, MA Lead Electronic Design Engineer Senior Sales Engineer **Electro-Mechanical Assembler**

<u>Careers</u>

Upcoming Events







The Battery Show September 12-14

> **Events** -

LabVIEW Enthusiasts



Bloomy hosts LabVIEW and TestStand training classes at our





With a new product release and demonstrations, featured keynotes, plus awards and accolades, Bloomy made a big showing at NIWeek 2017.



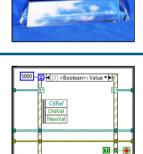


New EFT Module for TestStand Cuts Time to Production Test

Low-cost, out-of-the-box addon delivers full-featured architectures, eliminates most programming, and allows instrumentation swap-out without test sequence modification.



The award honors NI partners exhibiting the highest level of excellence, regional leadership, and mutual commitment to NI customer success.



User Interface Code Reuse in LabVIEW

In this blog, discover how Dynamic Events can be used to maximize code reuse in User Interfaces.



Bloomy Takes the Stage at NIWeek 2017

Bloomy's Business Unit Manager for Aerospace HIL and Real-Time Test, Roy Walker, highlighted Hardware-in-the-Loop (HIL) testing as a strategic application space that NI and Bloomy are collaboratively investing in.



BMS Testing Throughout the BMS Development Lifecycle In this video presentation you

training facilities in CT, MA and NJ.

Training Schedule



Interact with fellow LabVIEW enthusiasts to network, share coding practices, and discuss measurement and automation applications.

Mass Compilers

CT LUGNuts

will discover some of the techniques used for safe, efficient and repeatable BMS testing.



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